

10/030123

FILED UNDER 35 U.S.C. 371

PATENT NUMBER and
ISSUE DATE

U.S. UTILITY Patent Application

APPL NUM 10030123	FILING DATE 05/16/2002	CLASS 438 ²⁵	SUBCLASS 719	GAU 2812	EXAMINER 2812 Stephen Greene
**APPLICANTS: Hiramatsu Yasuji; Ito Yasutaka;					
**CONTINUING DATA VERIFIED: THIS APPLICATION IS A 371 OF PCT/JP01/04438 05/23/2001					
** FOREIGN APPLICATIONS VERIFIED: JAPAN 2000-156876 05/26/2000					
PG-PUB <input type="checkbox"/> DO NOT PUBLISH <input type="checkbox"/>		RESCIND <input type="checkbox"/>			
Foreign priority claimed 35 USC 119 conditions met		yes <input type="checkbox"/> no <input checked="" type="checkbox"/> yes <input type="checkbox"/> no <input checked="" type="checkbox"/>		ATTORNEY DOCKET NO 218478US2PCT	
Verified and Acknowledged Examiners's initials					
TITLE : Semiconductor manufacturing and inspecting device					

U.S. DEPT. OF COMM./PAT. & TM.-PTO-436L (Rev. 12-94)

NOTICE OF ALLOWANCE MAILED		CLAIMS ALLOWED	
		Total Claims	Print Claim for O.G.
ISSUE FEE		DRAWING	
Amount Due	Date Paid	Sheet Drwg.	Figs. Drwg. Print Fig.
<input type="checkbox"/> TERMINAL DISCLAIMER		Application Examiner	
		PREPARED FOR ISSUE	
WARNING: The information disclosed herein may be restricted. Unauthorized disclosure may be prohibited by the United States Code Title 35, Sections 122, 181 and 368, Possession outside the U.S. Patent & Trademark Office is restricted to authorized employees and contractors only.			

FILED WITH:

☐ DISK (CRF)☐ CD-ROM

(Attached in pocket on right inside flap)